Special Issue

Machine Vision Based Sensing and Imaging Technology

Message from the Guest Editor

Machine vision is a pivot technology for a number of imaging-based sensing techniques, ranging from automatic inspection to process control and robot guidance. Images here refer not only to conventional gray and color images from cameras, but also multispectral and hyperspectral imaging, 3D imaging, infrared imaging, and X-ray imaging, and they are now extensively studied for potential applications in manufacturing, agriculture, medicine, and defense. This Special Issue will be collection of state-of-the-art contributions from academics and industry on machine-vision-based sensing and imaging.

Guest Editor

Dr. Kaiwei Wang

State Key Laboratory of Modern Optical Instrumentation, Zhejiang University, Hangzhou 310027, Zhejiang, China

Deadline for manuscript submissions

closed (20 December 2022)



Sensors

an Open Access Journal by MDPI

Impact Factor 3.5 CiteScore 8.2 Indexed in PubMed



mdpi.com/si/106421

Sensors
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
sensors@mdpi.com

mdpi.com/journal/ sensors





Sensors

an Open Access Journal by MDPI

Impact Factor 3.5 CiteScore 8.2 Indexed in PubMed



About the Journal

Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro

Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), PubMed, MEDLINE, PMC, Ei Compendex, Inspec, Astrophysics Data System, and other databases.

Journal Rank:

JCR - Q2 (Instruments and Instrumentation) / CiteScore - Q1 (Instrumentation)

